EU Declaration of Conformity

(EMC)

Model : 150TFTx23xxx

Kind of Product: TFT monitor 23 inch

Applicant : Suzo International Nederland B.V.

Address : Antonie van Leeuwenhoekstraat 9 3261 LT Oud Beijerland Nederland

Manufacturer : Suzo International Nederland B.V.

Address : Antonie van Leeuwenhoekstraat 9 3261 LT Oud Beijerland Nederland

Test Standards : EN 55022 : 2010, CLASS B

EN 55024: 2010

We hereby declare,

Electromagnetic Compatibility Directives(2004/108/EC) are fulfilled, as laid out in the guideline set down by the member states of the European Directive. This declaration is valid for all samples that are part of this declaration, which are manufactured according to the production charts appendix.

Date of Issue: Jun 04, 2013

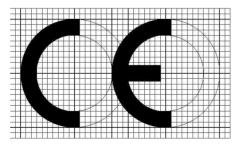
Certificate of conformity / Test report issued by :

Test Report Number : KR0140-CE-13013 EMC : EMC Labs Co., Ltd.

Technical documentation kept at:

Suzo International Nederland B.V.

Which will be made available upon request.



The CE conformity mark concern standards relevant for the EMC or LVD evaluation.

Signature

/president

(Name and Signature of Authorized Person)



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EMC TEST REPORT

Test Report File No KR0140-CE-13013

Date of Issue 2013.06.04

Date of Testing $2013.05.23 \sim 2013.05.25$

Model 150TFTx23xxx

TFT monitor 23 inch Kind of Product

Applicant Suzo International Nederland B.V.

Address Antonie van Leeuwenhoekstraat 9 3261 LT Oud Beijerland Nederland

Manufacture Suzo International Nederland B.V.

Address Antonie van Leeuwenhoekstraat 9 3261 LT Oud Beijerland Nederland

EN 55022: 2010, CLASS B **Test Standards**

EN 55024: 2010

EMC Labs Co., Ltd. **Testing Laboratory**

Complied **Test Result**

This product complies with the requirements of the EMC Directive 2004/108/EC.

The results in this report apply only to the sample tested.

This test report shall not be reproduced except in full, without the written Approval of EMC Labs Laboratory.

Tested by: Approved by: Y. J. Park Choi Y. 9 CHOI, YOUNG-SIK

PARK, YONG-JIN



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1. Test Regulation

■ Emission : EN 55022 : 2010

■ EN 55022: 2010

■ Class B Equipment□ Class A Equipment

□ Generic

☐ EN61000-3-2:2006 +A2:2009

☐ EN61000-3-3:2008

■ Immunity: EN 55024: 2010

■ EN 61000-4-2: 2009

■ EN 61000-4-3 :2006 +A2:2010

■ EN 61000-4-4: 2004 +A1:2010

☐ EN 61000-4-5 : 2006

■ EN 61000-4-6: 2009

☐ EN 61000-4-8 : 2010

☐ EN 61000-4-11 : 2004



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2. Applicant Information

Applicant : Suzo International Nederland B.V.

♦ Address : Antonie van Leeuwenhoekstraat 9 3261 LT Oud Beijerland Nederland

♦ Telephone Number: +31-(0)186-643333

Fax Number : +31-(0)186-643322

◆ E-mail : Johan.Somers@suzohapp.nl

♠ Contact Person : Mr.J.C.W.M. Somers

Manufacture : Suzo International Nederland B.V.

♠ Address : Antonie van Leeuwenhoekstraat 9 3261 LT Oud Beijerland Nederland



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3. Laboratory Information

Address

EMC Labs Co., Ltd.

Laboratory: #426 Shaum-Dong, Icheon-Shi, Gyeonggi-Do, 467-080

Telephone Number : +82-31-637-8895 Facsimile Number : +82-505-116-8895

FCC Filing No. : 88495 FCC CAB : KR0140

SITE MAP







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4. Equipment Under Test

4 1	1	T C	. •
/I I	General	Intorr	mation
7.1	Ochciai	ши	паноп

■ Table-Top	☐ Floor – Standing
-------------	--------------------

☐ Table-Top & Floor-Standing (Combination)

4.2 Configuration of the equipment under test

Equipment	Model	Manufacture	Serial No.
PC	DB-P60	SAMSUNG	185K98DP100422E
PRINTER	Laser 2100U	SAMBO	202A1012858
PS/2 KEYBOARD	PCK-200P	IMATION	090616987
SERIAL MOUSE	P801	SAMSUNG	01082759
USB MOUSE	M-UAE96	LG	HC7330J06RN
HEADSET	FS-850	FUSION FNC	-
DC POWER SUPPLY	OPE-305Q	ODA	oda-01-0923-01831

Type	Description	Connection	Spec.	Length(m)
DC Power	12V	DC POWER SUPPLY	Non-Shield	1.0
	VGA	PC	Shield	1.5
	DVI	PC	Shield	1.5
Signal				



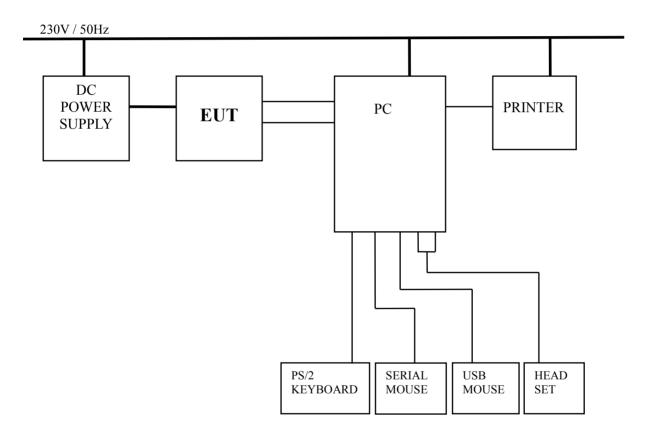
Report No.: KR0140-CE-13013 Page: 7 of 44

4.3 Operating Conditions

The equipment under test was operated during the measurement under following

Test mode	Normal Operating
1	"H" Pattern scrolling mode (Resolution – 1920x1080, 60Hz) (DVI mode, VGA mode)

4.4 The drawing of general test setup





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5. Summary of Test Result

5.1 Summary of EMI emission test result

EN 55022: 2010

Information technology equipment-Radio disturbance characteristics – Limits and methods of measurement.

23 1 1		
Test items		Result
Conducted Emission (Power Line)	EN55022:2010	Pass
(rower Line)	EN33022.2010	1 ass
Conducted Emission		
(Telecommunication Line)	EN55022:2010	Not Applicable
Radiated Emission		
(Below 1GHz)	EN55022:2010	Pass
Radiated Emission		
(Above 1GHz)	EN55022:2010	Pass

EN 61000-3-2: 2006, +A2: 2009

Limits for harmonic-current emissions (equipment input current up to including 16A per phase)

Test items	Test methods	Result
Harmonics	EN 61000-3-2 : 2006,+A2:2009	Not Applicable

EN 61000-3-3: 2008

Limitation of voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current ≤ 16A per phase and not subject to conditional connection

Test items	Test methods	Result
Flicker	EN 61000-3-3: 2008	Not Applicable

5.2 Summary of immunity test result

EN 55024: 2010

Information technology equipment-Immunity characteristics - Limits and methods of measurement.

Test items	Test methods	Result
Electrostatic discharge	EN 61000-4-2:2009	Pass
Electromagnetic field	EN 61000-4-3:2006+A2:2010	Pass
Electric fast transients	EN 61000-4-4:2004 +A1:2010	Pass
Surge	EN 61000-4-5:2006	Not Applicable
Conducted Immunity	EN 61000-4-6:2009	Pass
Magnetic field Immunity	EN 61000-4-8:2010	Not Applicable
Voltage dip/interruption	EN 61000-4-11:2004	Not Applicable



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5.3 Performance criteria

Performance criterion A: The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended.

The performance level may be replaced by a permissible loss of performance.

If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion B: After the test, the equipment shall continue to operate as intended without operator intervention.

No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the apparatus is used as intended.

The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test. If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as untended.

Performance criterion C: Loss of function is allowed, provided the function is self recoverable or can be restored by the operating of the controls by the user In accordance with the manufacturer's instructions.

Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.



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6. Test Results

6.1 Conducted Emission

Environmental Conditions

Temperature 22 °C

Humidity 46 % R.H.

Test Area Conducted Room

Test date 2013.05.23

6.1.1 Limits of conducted emission measurement

- AC main

Frequency	Class A (dB(µV))		Class B (dB(μ V))	
[MHz]	Quasi-peak	Average	Quasi-peak	Average
0.15 ~ 0.5	79	66	66 ~ 56 *	56 ~ 46*
0.5 ~ 5	73	60	56	46
5 ~ 30	73	60	60	50

^{*}The limit decreases linearly with the logarithm of frequency.

- Telecommunication

Frequency Class B Voltage Limits (dB(µV))		Current Lin	nits (dB(µA))	
[MHz]	Quasi-Peak	Average	Quasi-Peak	Average
0.15 ~ 0.5	84 to 74	74 to 64	40 to 30	30 to 20
0.5 ~ 30	74	64	30	20

^{*} The limits decrease linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5 MHz

^{*} The current and voltage disturbance limits are derived for use with an impedance stabilization Network (ISN) which presents a common mode (asymmetric mode) impedance of 150 Ω to the telecommunication port under test (conversion factor is 20 log₁₀ 150/I = 44 dB).



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6.1.2 Measurement procedure

Mains

The measurements were performed in a shielded room.

EUT was placed on a non-metallic table height of 0.8 m above the reference ground plane.

The rear of table was located 0.4 m to the vertical conducted plane.

EUT was power through the LISN, which was bonded to the ground plane.

The LISN power was filtered. Each EUT power lead, except ground (safety) lead, was individually connected through a LISN to input power source.

All I.O cables are positioned to simulate typical actual usage according to the test standard.

Both lines of power cord, hot and neutral, were measured.

6.1.3 Used equipments

Equipment	Model	Serial No.	Makers	Next Cal. Date	Used
Test Receiver	LSA-30	L07126026	LIG Nex1	2014.01.25	\boxtimes
LISN	ESH3-Z6	837950/023	R&S	2014.01.29	\boxtimes
LISN	ESH3-Z6	100329	R&S	2014.01.29	\boxtimes

6.1.4 Measurement uncertainty

Conducted emission measurement: (k=2, 95%)

9kHz-150 kHz : ± 3.263 [dB] 150kHz-30 MHz : ± 2.960 [dB]

6.1.5 Test data

- Note. QP = Quasi-Peak, AV= Average
- Loss = LISN Loss + Cable Loss
- Measurement time: 1 s



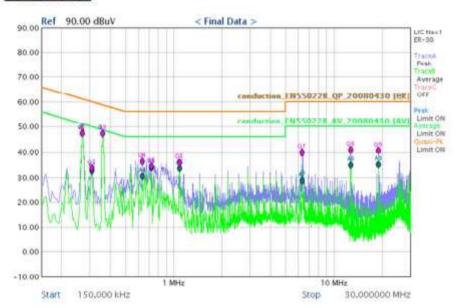
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6.1.6 Test Result

[HOT line] - DVI MODE

CONDUCTED EMISSION

SCREEN SHOT



FINAL TABLE

(Fina	al Table - Avera	ge]					
No	Freq (MHz)	Level (dBuV)	Corr (dB)	Limit (dBuV)	Margin (dB)	State	Reference
1	0.270000	47.22	0.32	51.12	3.90	Pass	AV
2	0.309000	32.61	0.27	50.00	17.39	Pass	AV
3	0.363000	47.08	0.20	48.66	1.58	Pass	AV
4	0.638000	30.34	0.27	46.00	15.66	Pass	AV
5	0.725000	33.72	0.27	46.00	12.28	Pass	AV
6	1.088000	33,71	0.20	46.00	12.29	Pass	AV
7	6.350000	28.72	0.25	50.00	21.28	Pass	AV
8	12.730000	34.86	0.46	50.00	15.14	Pass	AV
9	19.070000	35.00	0.45	50.00	15.00	Pass	AV
[Fina	al Table - Quasi-	Pk]					
No	Freq (MHz)	Level (dBuV)	Corr (dB)	Limit (dBuV)	Margin (dB)	State	Reference
1	0.270000	47.20	0.32	61.12	13.92	Pass	QP
2	0.309000	33.56	0.27	60.00	26.44	Pass	QP
3	0.363000	47.08	0.20	58.66	11.58	Pass	QP
4	0.638000	36.24	0.27	56.00	19.76	Pass	QP
5	0.725000	34.28	0.27	56.00	21.72	Pass	QP
6	1.088000	35.80	0.20	56.00	20.20	Pass	QP
7	6.350000	39.71	0.25	60.00	20.29	Pass	QP
8	12.730000	40.57	0.46	60.00	19.43	Pass	QP
9	19.070000	40.43	0.45	60.00	19.57	Pass	QP

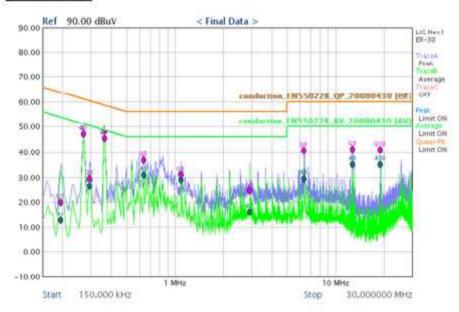


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[NEUTRAL line]

CONDUCTED EMISSION

SCREEN SHOT



FINAL TABLE

Fina	al Table - Avera	ge]					
No	Freq	Level	Corr	Limit	Margin	State	Reference
	(MHz)	(dBuV)	(dB)	(dBuV)	(dB)		
1	0.195000	12.52	0.36	53.82	41.30	Pass	AV
2	0.270000	46.88	0.29	51.12	4.24	Pass	AV
3	0.294000	26.45	0.27	50.41	23.96	Pass	AV
4	0.366000	45.11	0.28	48.59	3.48	Pass	AV
5	0.638000	30.87	0.26	46.00	15.13	Pass	AV
6	1.094000	29.08	0.17	46.00	16.92	Pass	AV
7	2.915000	15.95	0.25	46.00	30.05	Pass	AV
8	6.350000	29.39	0.31	50.00	20.61	Pass	AV
9	12.730000	35.14	0.43	50.00	14.86	Pass	AV
10	19.070000	35.12	0.43	50.00	14.88	Pass	AV
Fina	al Table - Quasi-	Pk]					
No	Freq	Level	Corr	Limit	Margin	State	Reference
	(MHz)	(dBuV)	(dB)	(dBuV)	(dB)		
1	0.195000	19.87	0.36	63.82	43.95	Pass	QP
2	0.270000	46.84	0.29	61.12	14.28	Pass	QP
3	0.294000	29.40	0.27	60.41	31.01	Pass	QP
4	0.366000	45.17	0.28	58.59	13.42	Pass	QP
5	0.638000	36.81	0.26	56.00	19.19	Pass	QP
6	1.094000	30.90	0.17	56.00	25.10	Pass	QP
7	2.915000	24.43	0.25	56.00	31.57	Pass	QP
8	6.350000	40.43	0.31	60.00	19.57	Pass	QP
9	12.730000	40.86	0.43	60.00	19.14	Pass	QP
10	19.070000	40.57	0.43	60.00	19.43	Pass	QP

* Comment:

- We've tested by DVI test mode for result, It's the worst case on the EMI test result between VGA and DVI test mode.



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6.2 Radiated emission

Environmental Conditions

Temperature 18 °C - Open Area Test site (10m)

21 °C - 3m Chamber

Humidity 64 % R.H. - Open Area Test site (10m)

40 % R.H. - 3m Chamber

Test Area Open Area Test site (10m) – Below 1GHz

3m Chamber – Above 1GHz

Test date 2013.05.23

6.2.1 Limits of radiated emission measurement

* Limits below 1 GHz

Frequency	Limit (Quasi-peak)
30 MHz ∼ 230 MHz	30 dB(μV/m)
230 MHz \sim 1000 MHz	37 dB(μV/m)

* Limits above 1 GHz

Frequency	Average limit	Peak limit
1 000 MHz \sim 3 000 MHz	50 dB(μV/m)	70 dB(μV/m)
3 000 MHz ~ 6 000 MHz	54 dB(μV/m)	74 dB(µV/m)

^{*} Note

The frequencies on which the transmitter part of the EUT is intended to operate shall be excluded from radiated emission measurements when performed in transmit mode of operation.

There shall be no frequency exclusion band applied to emission measurements of the receiver part of transceivers or the stand alone receiver under test, and/or associated ancillary equipment.

The exclusion band for immunity testing shall be calculated as follows:

- Lower limit of exclusion band = lowest allocated band edge frequency -5 %;
- Upper limit of exclusion band = highest allocated band edge frequency +5 %.

The lower limit applies at the transition frequency.

⁻ Exclusion bands.



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6.2.2 Measurement procedure

Mains

A pretest was performed at 3m distance in a semi-anechoic chamber for searching correct frequency.

The final test was done at a 10m open area test site with a quasi-peak detector.

EUT was placed on a non-metallic table height of 0.8m above the reference ground plane.

Cables were folded back and forth forming a bundle 0.3m to 0.4m long and were hanged at a 0.4m height to the ground plane.

Cables connected to EUT were fixed to cause maximum emission.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization.

The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

6.2.3 Used equipments

* Below 1GHz

Equipment	Model no	Makers	Serial no.	Next cal. date	Used
Test Receiver	ESVS 10	Rohde&Schwarz	846285/004	2014.01.25	\boxtimes
controller	ESDC-CT	EMC Labs	-	-	\boxtimes
Antenna master	ESDC-AM	EMC Labs	-	-	\boxtimes
Turn table	ESDC-TT	EMC Labs	-	-	\boxtimes
Bi-Log ANT	VULB9160	Schwarzbeck	VULB 9160- 3260	2013.08.05	\boxtimes

* Above 1GHz

Equipment	Model no	Makers	Serial no.	Next cal. date	Used
Spectrum Analyzer	E4440A	Agilent	MY43362353	2013.12.10	\boxtimes
controller	ACT	AUDIX	060552	-	\boxtimes
Antenna master	-	AUDIX	-	-	\boxtimes
Turn table	-	AUDIX	-	-	\boxtimes
Horn ANT	BBHA9120D	Schwarzbeck	974	2014.01.06	\boxtimes
Amplifier	ASF4-00100800- 28-20P-4	SELLEX	1663658	2013.12.10	\boxtimes



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6.2.4 Measurement uncertainty

Radiated Emission measurement : (k=2, 95%)

30-300 MHz ; 3 m: ±3.721 [dB], 10 m: +3.706, -3.707 [dB]

300-1000 MHz ; 3 m: ±3.818 [dB], 10 m: ±3.802 [dB]

6.2.5 Test data

* Receiving Antenna Mode: Horizontal, Vertical

* 10 m OATS

* Note: Reading = Test Receiver meter,

P= Polarization \rightarrow H = Horizontal, V = Vertical

Result = Field Strength (Antenna factor + Cable factor + Reading)

6.2.6 Test Result

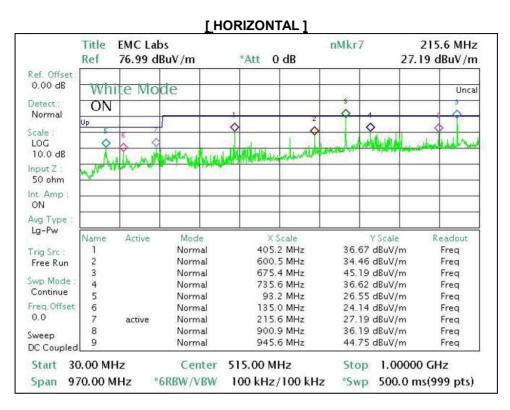
[Below 1GHz] - DVI MODE

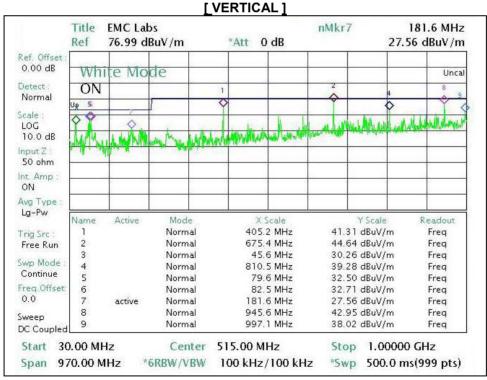
Cro guan av	Dooding		Height angle -		Correction		Limits	Decult
Frequency	Reading	Pol.	Height	angle	Antenna	Cable	LIIIIIIS	Result
[MHz]	[dB <i>µ</i> V]		[m]	[°]	[dB/m]	[dB]	[dB#V/m]	[dB <i>µ</i> V/m]
45.28	8.40	V	1.1	160	11.73	1.30	30	21.43
79.10	12.70	V	1.0	120	8.41	1.79	30	22.90
93.47	6.80	Н	4.0	270	8.00	1.93	30	16.73
404.90	10.30	V	1.3	90	15.69	4.62	37	30.61
674.89	6.20	Н	2.2	310	21.02	6.19	37	33.41
945.32	1.50	Н	1.5	240	24.20	7.56	37	33.26



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*3m Chamber Pre-scan Data





^{*} Comment:

- We've tested by DVI test mode for result, It's the worst case on the EMI test result between VGA and DVI test mode.



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[Above 1GHz] - DVI MODE

Frequency	Total Reading	Pol.	Limits	Margin	
[版]	[dB µV]		[dB µV/m]	[dB µV/m]	
2079.16	59.49	V	70	10.51	
2227.96	59.03	V	70	10.97	
1591.83	52.61	V	70	17.39	PK
1932.74	52.94	V	70	17.06	110
1042.60	50.48	н	70	19.52	
2227.63	51.60	Н	70	18,40	
2079,16	46.36	V	50	3.64	
2227.96	44.00	V	50	6.00	
1591.83	38.68	V	50	11.32	AV
1932.74	37.75	V	50	12.25	~v
1042.60	36.47	н	50	13.53	
2227.63	37.29	н	50	12.71	



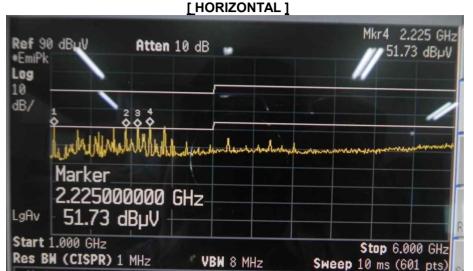
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*3m Chamber Data (Peak)

Marker

(1) (1)

(1) (1)



X Axis 1.042 GHz 1.933 GHz

2.075 GHz

2.225 GHz

Amplitude

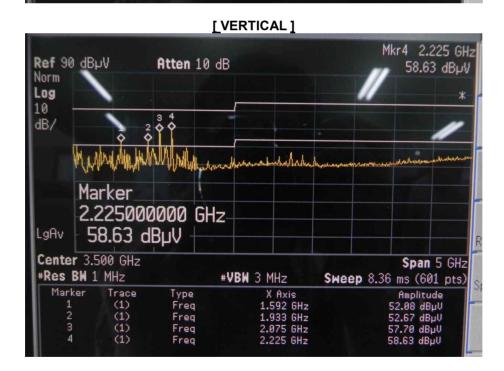
50.52 dBµV 50.52 dBµV 50.78 dBµV

51.73 dBµV

Type

Freq Freq Freq

Freq



* Comment:

- We've tested by DVI test mode for result, It's the worst case on the EMI test result between VGA and DVI test mode.



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6.3 Electrostatic Discharge

Environmental Conditions

Temperature 23 °C

Humidity 49 % R.H.

Atmosphere pressure 101.1 kPa

Test Area EMC Test Room

Test date 2013.05.24

6.3.1 Measurement procedure

A ground reference plane was located on the floor, and connected to earth via a low impedance connection.

The return cable of the ESD generator was connected to the reference plane. In case of floor standing equipment, EUT was placed on the reference plane on 0.1 m of insulating Support.

In case of table top equipment, EUT was placed on a wooden table 0.8m above the reference grounded floor.

A horizontal coupling plane(HCP) was placed on the table, and Connected to the reference plane via a 470 resistor located in each end (0.5mm insulating support between EUT and HCP).

In both cases a vertical coupling plane(VCP) OF 0.5 X 0.5m was located 10cm from the EUT's sides.

The VCP was connected to the reference plane in the same matter as the HCP.

6.3.2 Used equipments

Equipment	Model No.	Serial No.	Makers	Next Cal. Date	Used
ESD Tester	PESD1610	H810682	HAEFELY	2013.07.23	\boxtimes
НСР	-	-	-	-	\boxtimes
VCP	-	-	-	-	\boxtimes



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-	\sim	\sim		D .
h	3	٠.	Lect	Data
١,	,	,	LUST	17010

Test Specification: EN 6	1000-4-2
Kind of Discharges ⊠ Contact Discharge ⊠ Air Discharge ⊠ HCP / VCP (Indirect	Discharge)
Discharge Voltages	
	$: \pm 2 / 4 kV$
	: ± 2 / 4 / 8 kV
HCP / VCP	$:\pm 2/4 \mathrm{kV}$
Discharge Impedance	
\boxtimes 330 $\Omega/150$ pF	☐ 2KΩ/330pF
Number Of Discharge	
Number of discharges: 50 (Interval between	s per point, for each voltage and polarity discharges : $\geq 1s$)
Test point (Please refer	to attached photograph.)
Test Results ☑ Complied	☐ Not complied
Comment:	
1. There was no change of	of operation status during above testing.

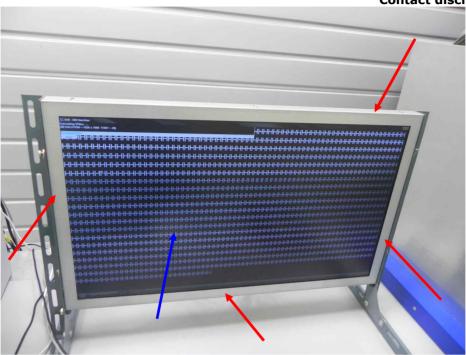
2. It's the same test result VGA test mode and DVI test mode.

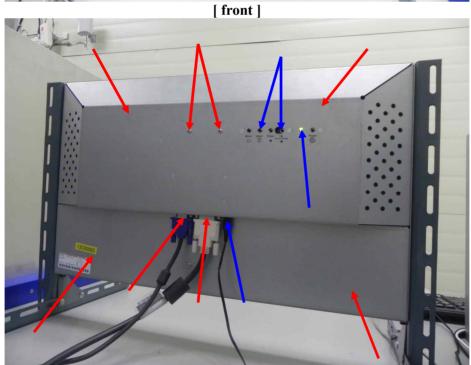


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Electrostatic Discharge (Test Point)

Air discharge ' Contact discharge





[rear]



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Contact Discharge

Test Point	Polarity	Discharge Levels (kV)	Results (criterion)
НСР	±	2 / 4 (kV)	A
VCP	±	2 / 4 (kV)	A
CASE	±	2 / 4 (kV)	A
SCREW	±	2 / 4 (kV)	A
VGA Port	±	2 / 4 (kV)	A
DVI Port	±	2 / 4 (kV)	A

Air Discharge

Test Point	Polarity	Discharge Levels (kV)	Results (criterion)
LCD	±	2 /4 /8 (kV)	A
BUTTON	±	2 /4 /8 (kV)	A
LED	±	2 /4 /8 (kV)	A
DC IN Port	±	2 /4 /8 (kV)	A



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6.4 Radio Frequency Electromagnetic Fields

Environmental Conditions

Temperature 23 °C

Humidity 44 % R.H.

Atmosphere pressure 100.9 kPa

Test Area RS Shield Room

Test date 2013.05.25

6.4.1 Measurement procedure

The test was performed at 3m full anechoic chamber.

For floor standing equipment, the EUT was standing on the floor.

For tabletop equipment, the EUT was located on a wooden table 0.8m above the floor.

The EUT was tested all sides, horizontal and vertical polarization.

The field uniformity was calibrated for 1V/m, 3V/m, 10V/m.

6.4.2 Used equipments

	Equipment	Model no.	Serial no.	Makers	Next Cal. date	Used
	Signal Generator	SME 03	R & S	842059/043	2014.03.27	\boxtimes
	Amplifier	150W1000M2	AR	0331745	-	\boxtimes
	Antenna	3142D	ETS LINDGREN	00102179	-	\boxtimes
EMC	Power Meter	E4419B	AGILENT	MY41291980	2014.05.24	\boxtimes
Labs	Power Head Sensor	E9304A	AGILENT	MY41499030	2014.05.24	\boxtimes
	Power Head Sensor	E9304A	AGILENT	MY41499039	2014.05.24	\boxtimes
	Directional Coupler	DC6180A	AR	0331175	2014.05.24	
	Filed Monitor	FM7004	AR	0330923	-	\boxtimes
	Field Probe	FP7003	AR	311519	2013.07.12	\boxtimes



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6.4.3 Test Data			
Test Specification : EN 61	000-4-3		
Frequency Range	☐ 1400 MHz – 2000MHz	☐ 2000 MHz – 2700 MHz	□ 80MHz – 2500MHz
Test level ☐ 1V/m	⊠ 3V/m	□ 10V/m	
Modulation ⊠ AM : 1kHz, 80% □ PM :			
Frequency step ☑ log 1% step	☐ log 3% step	log 5% step	
Dwell Time ☑ 3 s	☐ 2 s	☐ 1 s	
Test point ☐ Front (Horizontal / Ver ☐ Rear (Horizontal / Ver ☐ Left (Horizontal / Ver ☐ Right (Horizontal / Ver	rtical) tical)		
Test Results ⊠ Complied	☐ Not complied		
Comment:			
1. There was no change of	operation status during abor	ve testing.	

2. It's the same test result VGA test mode and DVI test mode.



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6.5 Electric Fast Transient/BURST

Environmental Conditions

Temperature 22°C

Humidity 51 % R.H.

Atmosphere pressure 100.7 kPa

Test Area EMC Test Room

Test date 2013.05.25

6.5.1 Measurement procedure

A ground reference plane was located on the floor.

EFT generator was connected to reference ground plane via low impedance connection.

For floor standing equipment, EUT was placed on a 0.1 m wooden table.

For tabletop equipment, EUT was placed on a wooden table(0.1m) above the reference plane.

Test generator and coupling/decoupling network was placed on, and bounded to, the ground reference plane.

When using the coupling clamp, the minimum distance between the coupling plates and all other conductive surfaces, except the ground reference plane beneath the coupling clamp, Shall be 0.5 m.

6.5.2 Used equipments

Equipment	Model No.	Serial No.	Makers	Next Cal. date	Used
EFT/B Tester	EMCPRO PLUS	0904221	Thermo KeyTek	2014.05.24	\boxtimes
Capacitive coupling clamp	CCL	-	Thermo KeyTek	2014.05.24	



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6.5.3 Used equipments

Test Specification	: EN 61000-4-4	
	ing (DC cable Length : Signal Lines	0.5m) Telecommunication line
Test level ☑ Power ☐ Signal Line ☐ Tel. line		
Burst frequency:	5 kHz, 5/50 ns	
Coupling Time :	> 60 s	
Test Results ☑ Complied		☐ Not complied

Coupling Point (DC main)	Polarity	Levels (kV)	Results (criterion)
L-N	±	1 (kV)	A

Coupling Point (Clamp)	Polarity	Levels (kV)	Results (criterion)
-	-	-	-

Comment:

- 1. There was no change of operation status during above testing.
- 2. It's the same test result VGA test mode and DVI test mode.



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6.6 Conducted Immunity

Environmental Conditions

Temperature 23 °C

Humidity 47 % R.H.

Atmosphere pressure 100.8 kPa

Test Area EMC Test Room

Test date 2013.05.25

6.6.1 Measurement procedure

A ground reference plane was located on the floor.

The EUT was isolated 0.1 m isolating support.

The ground plane was connected to floor reference ground plane via low impedance connection.

This test were Performed using CDN for mains, clamp for signal and injection probe.

6.6.2 Used equipments

Equipment	Model no.	Makers	Serial no.	Next Cal. date	Used
Signal Generator	8656B	НР	3334U13366	2013.10.04	\boxtimes
RF Power Amplifier	M75	Instruments for Industry	N935-0609	-	
Power Meter	E4419B	AGILENT	GB43312904	2013.09.25	\boxtimes
Attenuator (6dB)	58-6-33	WEINSCHEL	PZ356	2013.07.23	\boxtimes
Decoupling Network	F-2031-DCN- 23MM	FCC	091221	-	
EM Injection Clamp	F-2031-23MM	FCC	091219	2014.05.24	
CDN	F-801-M3-16A	FCC	091282	2014.05.24	
CDN	F-801-M2-16A	FCC	091770	2014.05.24	
Directional Coupler	DC2600A	AR	0331437	2014.05.24	\boxtimes
Power Head Sensor	E9301A	AGILENT	US39212396	2013.09.25	
Power Head Sensor	E9301A	AGILENT	US39210340	2013.09.25	\boxtimes



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6.6	.3 Test Data						
Tes	est Specification : EN 61000-4-6						
	quency Range 150 kHz – 80MHz	<u> </u>	50 kHz - 230MHz	□150 kHz - 500M	ΙΗz		
	eation of Coupling (DC Power		ength : 0.3m) al Lines	☐Telecommunicatio	n line		
Tes	t level 1V	\boxtimes	3V	☐ 10V			
\boxtimes	Modulation ☑ AM : 1kHz, 80% ☐ PM : 1Hz (0.5 s ON : 0.5 s OFF)						
	quency step log 1% step		g 3% step	☐ log 5% step			
Dw	rell Time 3 s	□ 2	S	☐ 1 s			
	t Results Complied	□ N	ot complied				
	Coupling Point (I	OC)	Coupling Metho	od Results (criteri	on)		
	POWER		CDN (M2)	A			

Coupling Method

Comment:

- 1. There was no change of operation status during above testing.
- 2. It's the same test result VGA test mode and DVI test mode.

Coupling Point (Signal)

Results (criterion)



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7. Test Photographs

Radiated Emission (Below 1GHz)

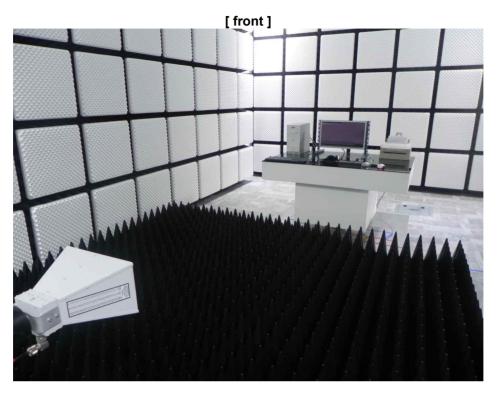


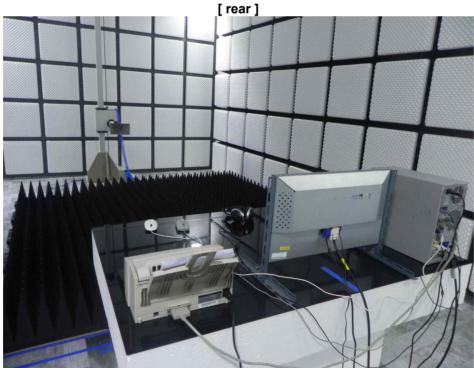




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Radiated Emission (Above 1GHz)







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Conducted Emission (Main Power)

[front]



[rear]





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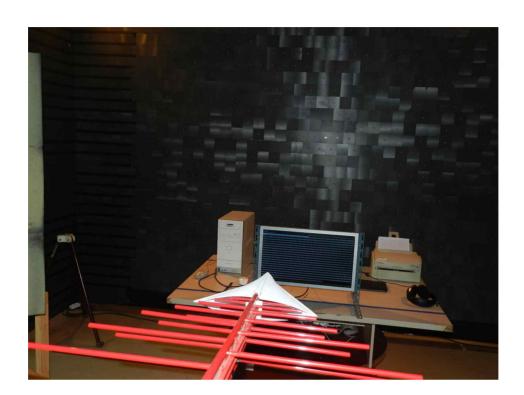
Electrostatic Discharge





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Radio frequency electromagnetic field





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Electric Fast Transient





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Conducted Immunity





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8. E.U.T. Photographs





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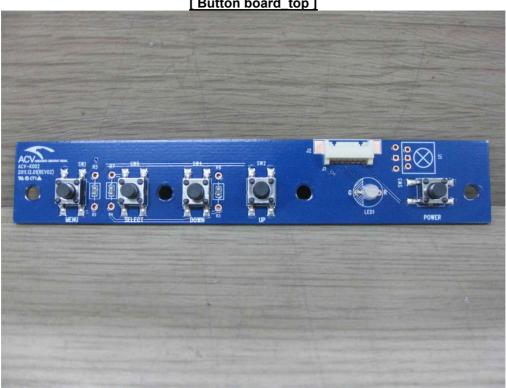




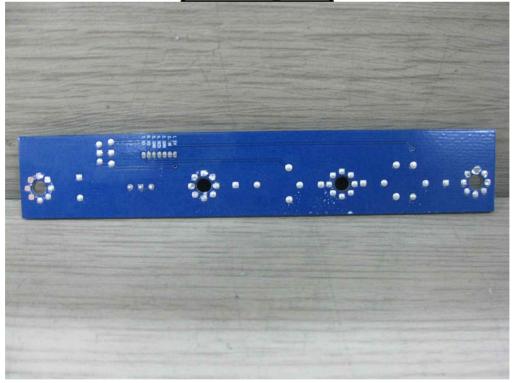


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[Button board_bottom]



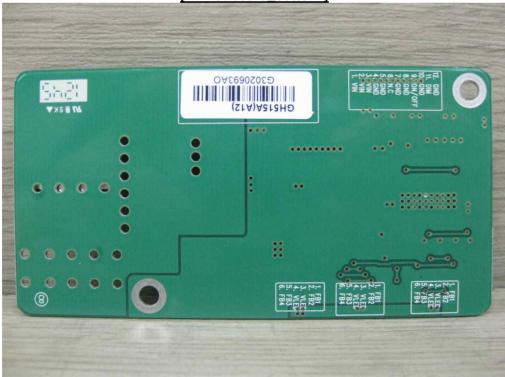


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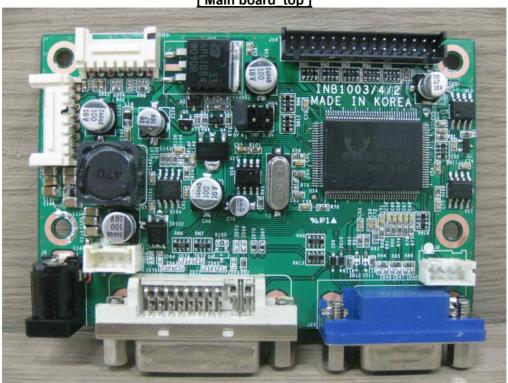
[Driver board_bottom]



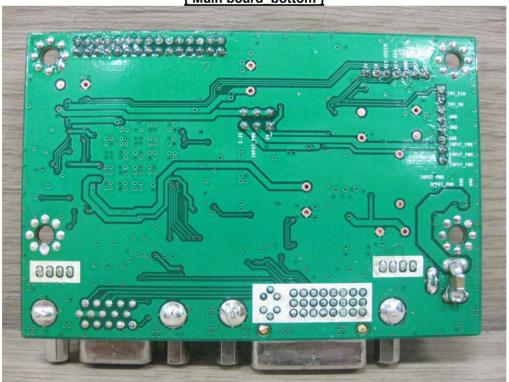


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[Main board_top]



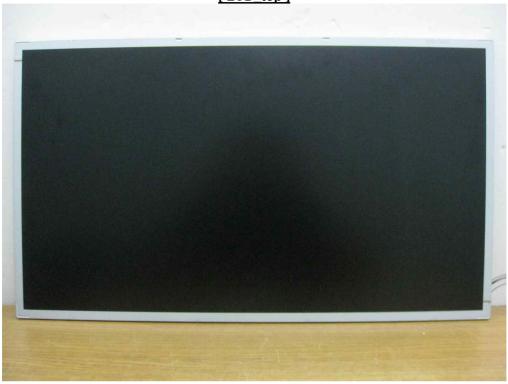
[Main board_bottom]





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[LCD_bottom]





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